Accurate Generation of Scan Enable Signal when Testing Integrated Circuits Using Sequential Scanning Techniques

Abstract

An accurate scan enable signal may be generated from an external scan enable (e.g., generated by test equipment). The external scan enable signal may contain transitions from scan mode to capture mode, and vice versa. The accurate scan enable signal may be generated to time transitions from scan mode to capture mode synchronous with a clock signal, and pass the transitions from capture mode to scan mode asynchronously.